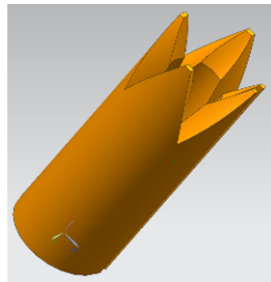


C series probe is developed by our core competence micro tooling design and fabrication technology, to fit the mass production with high volume requirements. Our special design can the crown tip easily penetrating the DUT surface and our recordable manufacture process can control the electrical performance better than similar product in the market. The C series probe is quite fit the Memory Test and Burn-in test industry.



Special cylindrical Crown



Progressive precision tools layout

Characters:

- Special Crown tip design easier penetrate the DUT Sn surface
- Same Maximum travel but shorter probe free length
- Enough spring probe internal space make higher force possible
- Uniform plating inside
- Total cost advantage and capacity rump up quickly

